



## N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	100				
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	0.086			
Q <sub>g</sub> (Max.) (nC)	72				
Q <sub>gs</sub> (nC)	11				
Q <sub>gd</sub> (nC)	32				
Configuration	Single				

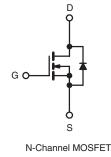
#### **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available



RoHS COMPLIANT





<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	100	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$	- I <sub>D</sub>	18		
	VGS AL TO V	T <sub>C</sub> = 100 °C		12	A	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	68	1	
Linear Derating Factor				0.32	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	720	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	17	A	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	4.8	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	48	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>	7 0	
Mounting Torque	6-32 or l	6-32 or M3 screw		10	lbf ⋅ in	
				1.1	N ⋅ m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 3.7 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 17 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 17 \text{ A}$ , dI/dt  $\le 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.

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THERMAL RESISTANCE RAT	TINGS								
PARAMETER	SYMBOL	TYP. MAX.			UNIT				
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65							
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 3.1				°C/W			
<b>SPECIFICATIONS</b> $T_J = 25 °C$ ,	unless otherw	vise noted							
PARAMETER	SYMBOL		CONDITI	ONS	MIN.	TYP.	MAX.	UNIT	
Static					1	1	1	1	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0$	V, I <sub>D</sub> = 2	50 μA	100	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to			-	0.13	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{C}$	<sub>3S</sub> , I <sub>D</sub> = 2	50 μA	1.0	-	3.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub>	$_{3} = \pm 20$	V	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	25		
		$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 150 ^{\circ}\text{C}$			-	-	250	μA	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	Ι <sub>D</sub>	= 10 A <sup>b</sup>	-	0.086	-	Ω	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 50	0 V, I <sub>D</sub> =	10 A <sup>b</sup>	9.1	-	-	S	
Dynamic		1						1	
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ ,		-	1700	-			
Output Capacitance	C <sub>oss</sub>	VD	s = 25 V		-	560	-	_	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5 f = 1.0 MHz		-	120	-	pF		
Drain to Sink Capacitance	С			-	12	-			
Total Gate Charge	Qg				-	-	72	nC	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		A, V <sub>DS</sub> = 80 V, g. 6 and 13 <sup>b</sup>	-	-	11		
Gate-Drain Charge	Q <sub>gd</sub>		366 116	J. 0 and 15	-	-	32		
Turn-On Delay Time	t <sub>d(on)</sub>				-	11	-		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 50 V, I <sub>D</sub> = 17 A, R <sub>G</sub> = 9.1 $\Omega$ , R <sub>D</sub> = 2.9 $\Omega$ , see fig. 10 <sup>b</sup>		-	44	-	ns		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	53	-			
Fall Time	t <sub>f</sub>			-	43	-			
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH		
Internal Source Inductance	Ls			-	7.5	-			
Drain-Source Body Diode Characteristic	s				1	1	1		
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	17	A		
Pulsed Diode Forward Currenta	I <sub>SM</sub>			-	-	68			
Body Diode Voltage	$V_{SD}$	$T_{J} = 25 \ ^{\circ}C, \ I_{S} = 17 \ A, \ V_{GS} = 0 \ V^{b}$		-	-	2.5	V		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \ ^{\circ}C, \ I_F = 17 \ A, \ dI/dt = 100 \ A/\mu s^b$		-	180	360	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.3	2.6	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$						_D)	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

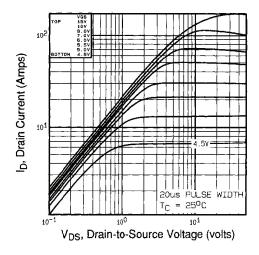


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

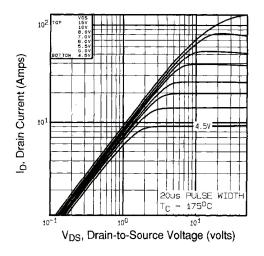


Fig. 2 - Typical Output Characteristics,  $T_C = 175$  °C

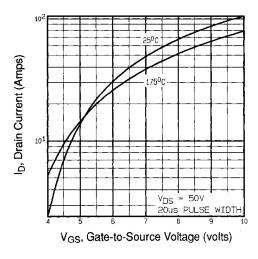


Fig. 3 - Typical Transfer Characteristics

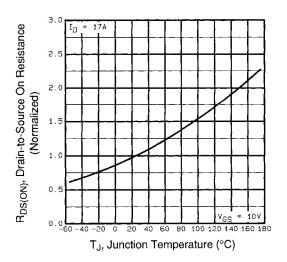


Fig. 4 - Normalized On-Resistance vs. Temperature

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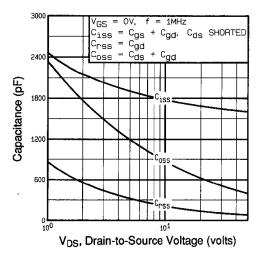


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

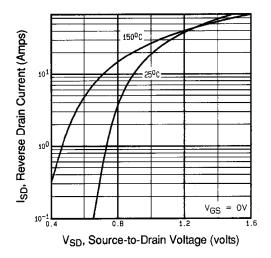


Fig. 7 - Typical Source-Drain Diode Forward Voltage

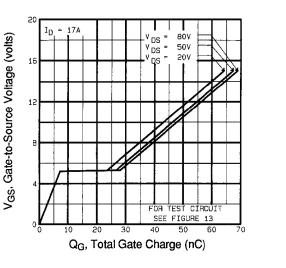


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

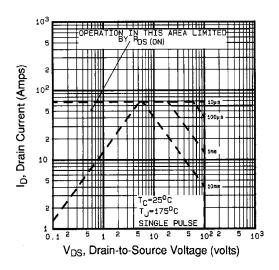


Fig. 8 - Maximum Safe Operating Area

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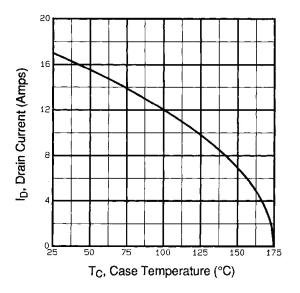


Fig. 9 - Maximum Drain Current vs. Case Temperature

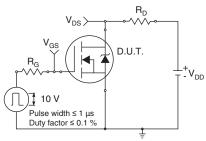


Fig. 10a - Switching Time Test Circuit

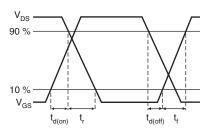
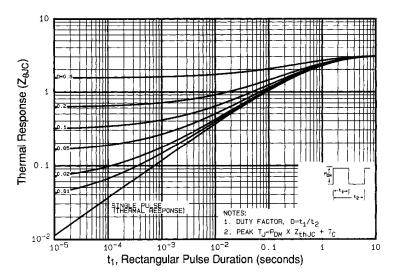


Fig. 10b - Switching Time Waveforms





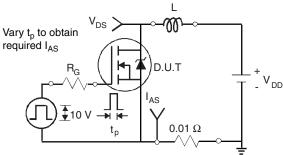


Fig. 12a - Unclamped Inductive Test Circuit

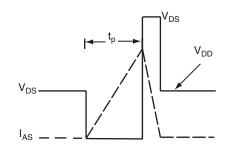


Fig. 12b - Unclamped Inductive Waveforms



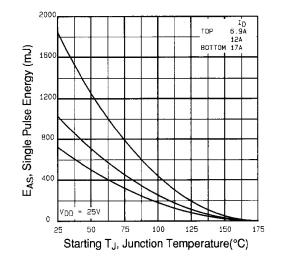


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

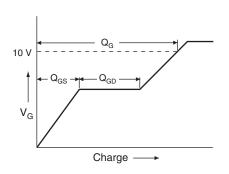


Fig. 13a - Basic Gate Charge Waveform

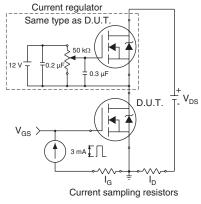
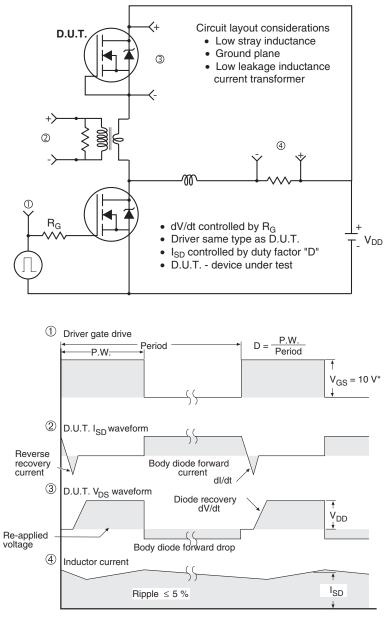


Fig. 13b - Gate Charge Test Circuit





Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS}$  = 5 V for logic level devices

Fig.14 - For N-Channel



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